

**RELIABILITY DATA**  
**LTC1955 / LTC4307 / LTC4308 / LTC4309 / LTC4310 / LTC4311**

**9/11/2008**

• **OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SOIC/SOT/MSOP	77	0722	0722	77.02	0
QFN/DFN	154	0723	0750	154.02	0
	231			231.05	0

• **PRESSURE COOKER TEST AT 15 PSIG, +121°C <sup>(4)</sup>**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	380	0628	0711	101.50	0
SSOP/TSSOP	503	0226	0444	171.13	0
QFN/DFN	200	0440	0523	4.80	0
	1,083			277.43	0

• **TEMP CYCLE FROM -65°C to +150°C <sup>(4)</sup>**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	293	0630	0716	293.00	0
SSOP/TSSOP	580	0226	0444	539.21	0
QFN/DFN	250	0440	0523	25.00	0
	1,123			857.21	0

• **THERMAL SHOCK FROM -65°C to +150°C <sup>(4)</sup>**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	293	0630	0716	293.00	0
SSOP/TSSOP	127	0329	0444	127.00	0
QFN/DFN	199	0440	0509	19.90	0
	619			439.90	0

(1) Assumes Activation Energy = 0.7 Electron Volts  
(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 30.74 FITS  
(3) Mean Time Between Failures in Years = 3,711  
(4) Environmental Stress data is presented by Process Technology family.  
Note: 1 FIT = 1 Failure in One Billion Hours.